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Form PTO 1449
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U.S. Department of Commerce
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App. Docket No.
Mo-6644 LeA-34 976

Serial No.
29 998 560

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Applicant
Kristina Vogt et al.

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U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
L.T.M.-E	AA <u>4915870</u>	04 10 90	Jones	252	313.2	
	AB					
	AC					
	AD					
	AE					
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	AI					
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FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						Yes	No*
L.T.M.-E	EP 0 634 465 A1	01/18/95	Europe				
	AM						
	AN						
	AO						
	AP						

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

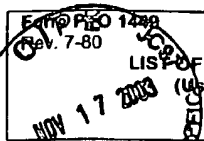
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	U.S. Department of Commerce Patent and Trademark Office		Atty. Docket No. Mo-6644/LeA-34,976	Serial No. 09/998,560
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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	5,614,449	03/25/97	Jensen	501	38	
	AB	5,755,946	05/26/98	Ferronato	205	110	
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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							Yes	No*
297/E	AL	164439	10/31/75	Hungary				x
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	AP							

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EXAMINER	Lynette J. Almazan	DATE CONSIDERED 4/22/2004
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Mo6644-LeA 34.976

Serial No.

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U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
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JC973 U.S. PTO
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 11/29/01

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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							Yes	No*
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LJME	AM	WO 00/24842	05/04/2000	World Patent	—	—		
LJME	AN	WO 99/64527	12/16/99	World Patent	—	—		
LJME	AO	WO 99/47618	09/23/99	World Patent	—	—		
LJME	AP	WO 99/67056	12/29/99	World Patent	—	—		

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LJME	AR	Microchip Fabrication: A Practical Guide to Semiconductor Processing, Peter Van Zant ed., McGraw-Hill (month unavailable) 2000, pages 302-309 & 401-403
LJME	AS	Copper CMP: A Quistion of Tradeoffs, Peter Singer, Semiconductor International, Verlag Cahnner, May 2000, pages 73-84
LJME	AT	Chemical Mechanical Planarization of Microelectronic Material, J.M. Steigerwald, S.P. Murarka & R.J. Gutmann, John Wiley & Sons, Inc. (month unavailable) 1997, CMP Variable and Manipulations, pages 42-43
EXAMINER		DATE CONSIDERED
Lynette T. Olney-Eumini		4/22/2004
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